

SKiiP 1003GB171-2DW

I. Power section 2 * SKiiP503GB171CT per phase

Absolute maximum ratings			
Symbol	Conditions ¹⁾	Values	Units
IGBT			
V _{CES}	Operating DC link voltage	1700	V
V _{CC}		1200	V
V _{GES}		± 20	V
I _C		T _{Heat sink} = 25 (70) °C	1000 (750)
Inverse diode			
I _F	T _{Heat sink} = 25 (70) °C	1000 (750)	A
I _{FSM}	T _j = 150 °C, t _p = 10ms; sin	8640	A
I ² t (Diode)	Diode, T _j = 150 °C, 10ms	373	kA ² s
T _J , (T _{stg})		-40...+150 (125)	°C
V _{isol}	AC, 1min.	4000	V
I _{C-package}	T _{Heat sink} = 70°C, T _{Term} ³⁾ =115°C	2 * 500	A

Characteristics		min.	typ.	max.	Units
Symbol	Conditions ¹⁾				
IGBT					
$V_{CESat}^{5)}$	$I_C = 600A, T_J = 25\ (125)^{\circ}C$	—	2,7 (3,1)	3,2	V
V_{CEO}	$V_{GE} = 15V; T_J = 25\ (125)^{\circ}C$	—	1,5 (1,6)	1,7 (1,8)	V
r_{CE}	$V_{GE} = 15V; T_J = 25\ (125)^{\circ}C$	—	2,1 (2,8)	2,7 (3,3)	mΩ
$E_{on} + E_{off}^{4)}$	$\left\{ \begin{array}{l} I_C=600A \quad V_{CC}=900V \\ T_J=125^{\circ}C \quad V_{CC}=1200V \end{array} \right.$	—	600	—	mJ
		—	885	—	mJ
I_{CES}	$V_{GE}=0, V_{CE}=V_{CES}, T_J=25(125)^{\circ}C$	—	2,4 (144)	—	mA
L_{CE}	top, bottom	—	5	—	nH
R_{CC-EE}	resistance, terminal-chip	—	0,20	—	mΩ
Inverse diode					
$V_F^{5)}) = V_{EC}$	$I_F = 600A; T_J = 25(125)^{\circ}C$	—	2,0 (1,8)	2,3	V
V_{TO}	$T_J = 25\ (125)^{\circ}C$	—	1,5 (1,2)	1,7 (1,4)	V
r_T	$T_J = 25\ (125)^{\circ}C$	—	1,0 (1,2)	1,2 (1,3)	mΩ
$E_{RR}^{4)}$	$\left\{ \begin{array}{l} I_C=600A \quad V_{CC}=900V \\ T_J=125^{\circ}C \quad V_{CC}=1200V \end{array} \right.$	—	72	—	mJ
		—	105	—	mJ
Thermal characteristics					
R_{thjs}	per IGBT	—	—	0,028	°C/W
R_{thjs}	per diode	—	—	0,055	°C/W
$R_{thsa}^{2)})$	W: NWK 40; 8l/min; 50%glyc.	—	—	0,013	°C/W
Current sensor					
$I_{p\ RMS}$	$T_a=100^{\circ}C, V_{Supply} = \pm 15V$	—	2 * 400	—	A
$I_{pmax\ RMS}$	$t \leq 2\ s, T_a=100^{\circ}C$	—	2 * 500	—	A
Mechanical data					
M1	DC terminals, SI Units	4	—	6	Nm
M2	AC terminals, SI Units	8	—	10	Nm

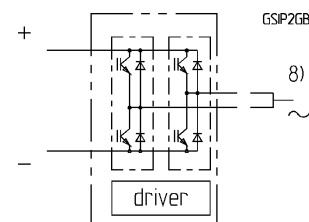
SKiiP[®] 3

SK integrated intelligent Power PACK 2-pack

SKiiP 1003GB171-2DW²⁾

Target data

housing S23



Features

- SKiiP technology inside
 - pressure contact of ceramic to heat sink; low thermal impedance
 - pressure contact of main electric terminals
 - pressure contact of auxiliary electric terminals
 - increased thermal cycling capability
 - low stray inductance
 - homogenous current distribution
- CAL diode technology
- integrated current sensor
- integrated temperature sensor
- high power density

1) $T_{heatsink} = 25\ ^\circ C$, unless otherwise specified

2) D integrated gate driver
U with DC-bus voltage measurement (option for GB)
L mounted on standard heat sink for forced air cooling
W mounted on standard liquid cooled heat sink

3) T_{term} = temperature of terminal

4) with SKiiP 3 gate driver

5) Measured at chip level

6) external paralleling necessary

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